

A new measure for calculating multiple fault coverage of microprocessor self-test

Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.ester.ee/record=b2150914*est

Application specific true critical paths identification in sequential circuits

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan; Devadze, Sergei; Oyeniran, Adeboye Stephen 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 299-304 : ill <https://doi.org/10.1109/IOLTS.2019.8854442>

Combined pseudo-exhaustive and deterministic testing of array multipliers

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 21st edition, 24th-26th May, Cluj-Napoca, Romania : proceedings 2018 / 6 p. : ill <https://doi.org/10.1109/AQTR.2018.8402708>

Double phase fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Josifovska, Galina; Oyeniran, Adeboye Stephen DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

Environment for innovative university research training in the field of digital test

Oyeniran, Adeboye Stephen; Ademilua, Tolulope; Kruus, Margus; Ubar, Raimund-Johannes 2021 30th Annual Conference of the European Association for Education in Electrical and Information Engineering (EAEIE) 2021 <https://doi.org/10.1109/EAEIE50507.2021.9531003>

From online fault detection to fault management in network-on-chips : a ground-up approach

Azad, Siavoosh Payandeh; Niazmand, Behrad; Janson, Karl; Nevin, George; Oyeniran, Adeboye Stephen; Putkaradze, Tsotne; Apneet Kaur; Raik, Jaan; Jervan, Gert; Ubar, Raimund-Johannes; Hollstein, Thomas Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems (DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 48-53 : ill <https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

High-level combined deterministic and pseudo-exhaustive test generation for RISC processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Gürsoy, Cemil Cem; Raik, Jaan 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791526>

High-Level Combined Deterministic and Pseudo-exhaustive Test Generation for RISC Processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan 2019 IEEE European Test Symposium (ETS) : ETS 2019, May 27-31, 2019, Baden-Baden, Germany : Proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791526>

High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test

Oyeniran, Adeboye Stephen; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes 2022 IEEE Computer Society Annual Symposium on VLSI (ISVLSI) : Nicosia, Cyprus : 04-06 July 2022 2022 / p. 32-37 <https://doi.org/10.1109/ISVLSI54635.2022.00019>

High-level functional test generation for microprocessor modules

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes Proceedings of 26th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2019 : Rzeszów, Poland, June 27 - 29, 2019 2019 / p. 356-361 : ill <https://doi.org/10.23919/MIXDES.2019.8787131>

High-Level Implementation-Independent Functional Software-Based Self-Test for RISC Processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan Journal of electronic testing : theory and applications 2020 / p. 87-103 <https://doi.org/10.1007/s10836-020-05856-7>

High-level implementation-independent software-based self-test for RISC type microprocessors = Mikroprotsessorite tarkvarapõhine implementatsioonist mittedõltuv funktsionaalne enesekontroll

Oyeniran, Adeboye Stephen 2020 <https://digikogu.taltech.ee/et/Item/08a75fbb-3f71-4fe4-b3d0-3f37a9a5f36d>

High-level modeling and testing of multiple control faults in digital systems

Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

High-level test data generation for software based self-test in microprocessors

Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

High-level test generation for processing elements in many-core systems

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Azad, Siavoosh Payandeh; Raik, Jaan 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 / 8 p. : ill <http://dx.doi.org/10.1109/ReCoSoC.2017.8016156>

Implementation-independent functional test for transition delay faults in microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan 2020 23rd Euromicro Conference on Digital System Design (DSD), 26-28 August 2020, Kranj, Slovenia 2020 / p. 646-650 <https://doi.org/10.1109/DSD51259.2020.00105>

Implementation-independent functional test generation for RISC microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920323>

Implementation-independent test generation for a large class of faults in RISC processor modules

Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Raik, Jaan; Ubar, Raimund-Johannes 24th Euromicro Conference on Digital System Design (DSD) 2021 <https://doi.org/10.1109/DSD53832.2021.00090>

Minimization of the high-level fault model for microprocessor control parts [Online resource]

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Medaiyese, Olusiji BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill <https://doi.org/10.1109/BEC.2018.8600980>

Mixed-level identification of fault redundancy in microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Gürsoy, Cemil Cem; Raik, Jaan LATS 2019 : 20th IEEE Latin American Test Symposium : Santiago, Chile, March 11th - 13th 2019 2019 / 6 p. : ill <https://doi.org/10.1109/LATW.2019.8704591>

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill <http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault testing in systems-on-chip with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 2015 / p. 66-71 : ill <http://dx.doi.org/10.1109/IDT.2015.7396738>

New categories of Safe Faults in a processor-based Embedded System

Gürsoy, Cemil Cem; Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Piumatti, Davide; Raik, Jaan; Sonza Reorda, Matteo; Ubar, Raimund-Johannes 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 4 p. : ill <https://doi.org/10.1109/DDECS.2019.8724642>

On test generation for microprocessors for extended class of functional faults

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC: New technology enabler : 27th IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2019 Cusco, Peru, October 6-9, 2019 : Revised and Extended Selected Papers 2020 / p. 21-44 <https://doi.org/10.1007/978-3-030-53273-4> [Conference proceedings at Scopus](#) [Article at Scopus](#)

Parallel pseudo-exhaustive testing of array multipliers with data-controlled segmentation

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Symposium on Circuits and Systems (ISCAS) : 27-30 May 2018, Florence, Italy : proceedings 2018 / 5 p.: ill <https://doi.org/10.1109/ISCAS.2018.8350936> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Replication-based deterministic testing of 2-dimensional arrays with highly interrelated cells

Azad, Siavoosh Payandeh; Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 21-26 : ill <https://doi.org/10.1109/DDECS.2018.00011>

Software-based self-test with decision diagrams for microprocessors

Ubar, Raimund-Johannes; Jasnetski, Artjom; Tšertov, Anton; Oyeniran, Adeboye Stephen 2018

Teaching digital system test

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus The 27th EAAEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p

True path tracing in structurally synthesized BDDs for testability analysis of digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Oyeniran, Adeboye Stephen; Jenihhin, Maksim Euromicro Conference on

